



**4) Please explain how a product is modeled within your functional test coverage method. Is it modeled by... (check all that apply)**

- a) Component
- b) Function
- c) Subassembly
- d) To pin level
- e) Other (please specify)

**5) How is defect coverage verified? (Examples of defects for structural test are: part presence, correct part, orientation, part is live, alignment, shorts, opens, solder quality. For functional test, examples are: feature or functional block operational, at-speed capability, measured parameter, such as voltage, current, frequency, CRC, etc.) Check all that apply:**

- a) Fault injection
- b) Analyzing schematics and specs
- c) Analyzing return data
- d) Other (please specify)

**6) What data is required within the model for critical test decisions? For example:**

**a) Meeting quality requirements (e.g. X% coverage of all functional blocks, Y% coverage of all critical blocks, full speed testing of all interfaces) Data required:**

- (1) Feature or function block coverage
- (2) Coverage to component level
- (3) Coverage to pin level
- (4) Coverage percentage
- (5) Other (please specify)

**6 (continued) What data is required within the model for critical test decisions? For example:**

**b) Comparing the coverage of different HW/SW test revisions. Data required:**

- (1) Feature or function block coverage
- (2) Coverage to component level
- (3) Coverage to pin level
- (4) Coverage percentage
- (5) Summary of differences between revisions
- (6) Other (please specify)

**c) Comparing the coverage of different test environments. Data required:**

- (1) Feature or function block coverage
- (2) Coverage to component level
- (3) Coverage to pin level
- (4) Coverage percentage
- (5) Summary of differences between environments
- (6) Other (please specify)

**d) Comparing the coverage of different test stages (for example, comparing coverage between AXI, ICT and functional test). Data required:**

- (1) Coverage to component level
- (2) Coverage to pin level
- (3) Coverage percentage
- (4) Summary of differences between environments
- (5) Other (please specify)

**e) Leveraging previous coverage assessments of reused blocks. Data required:**

- (1) Feature or function block coverage
- (2) Coverage to component level
- (3) Coverage to pin level
- (4) Coverage percentage
- (5) Summary of differences between environments
- (6) Other (please specify)

**(f) Other critical test–related decisions not listed above, and data required (please specify):**

**7) Does your functional test coverage model take into account other test stages in the manufacturing test process in order to prevent test redundancies — for example, how the model behaves when coverage overlap occurs between test stations (FT, ICT, inspection and boundary scan)?**

Yes

No

**8) How is functional test coverage integrated with other manufacturing test stage coverage models (ICT, AOI and AXI)?**

The coverage used to identify test gaps to ensure coverage between test stages

The coverage used to identify test redundancies between test stages

The coverage used for other purposes (please specify)

**9) a) Does your company have a tool that you are currently using?**

Yes

No

**b) If yes, is this a third party developed tool or was it internally developed?**

Internal

3<sup>rd</sup> party

**c) If yes, please provide a brief description of the tool and how it works.**

**10) Please list all the inputs, requirements, outputs and assumptions of this tool**

**a) Inputs/Requirements**

- (1)
- (2)
- (3)
- (4)
- (5)
- (6)

**b) Outputs**

- (1)
- (2)
- (3)
- (4)
- (5)
- (6)

**c) Assumptions**

- (1)
- (2)
- (3)
- (4)
- (5)
- (6)

**11) Would you be willing to present/share your company's coverage method with the iNEMI Functional Test Project team?**

- Yes (please provide contact information, question #13)
- No

**12) Would you like to participate in the iNEMI Functional Test Project?**

- Yes (please provide contact information, question #13)
- No

**13) Please provide your contact information:**

Name:

Company:

E-mail:

Phone: